



#### Advanced Controller Technology for 3D NAND Flash Wei Lin

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- The Reliability Issues of 3D NAND Flash
- The Architecture of Error Handling Technology
- Error Correction Technology
- Comparison between ECC engines
- Reliability of SSD with 3D NAND Flash memory
- Conclusion



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### mory The Reliability Issues of 3D NAND

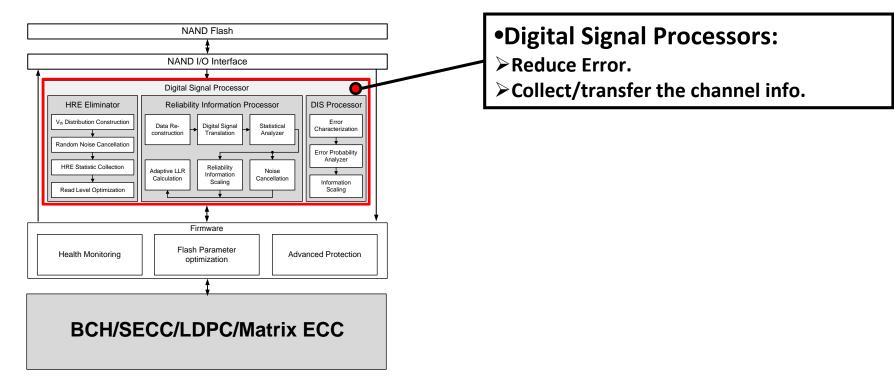
- Fast de-trapping of programmed electron
- Layer Dependency
- Different erase mechanism from 2D NAND
- Different retention behavior from 2D NAND
- Weak read disturb immunity
- Weak program disturb immunity



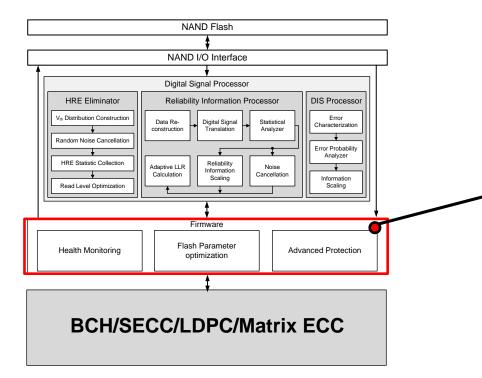
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## Flash Memory Error Handling Tech. in Controller

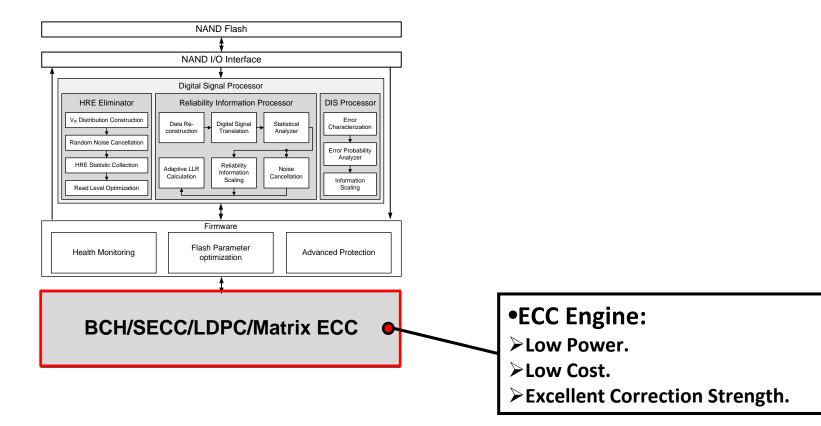




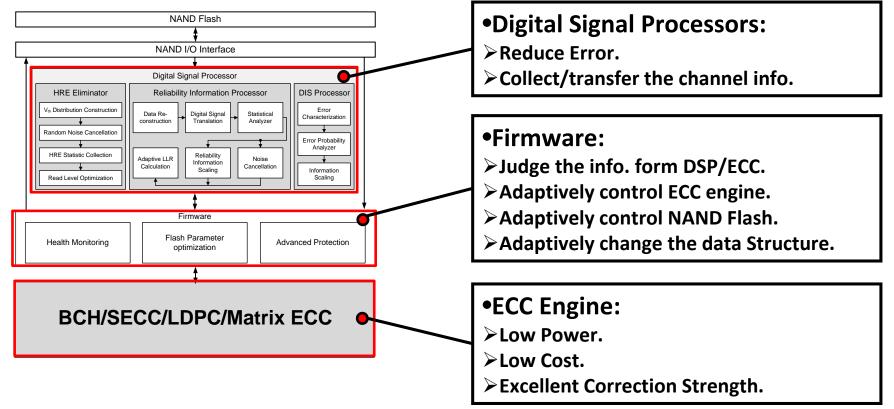


# Firmware: Judge the info. form DSP/ECC. Adaptively control ECC engine. Adaptively control NAND Flash. Adaptively change the data Structure.







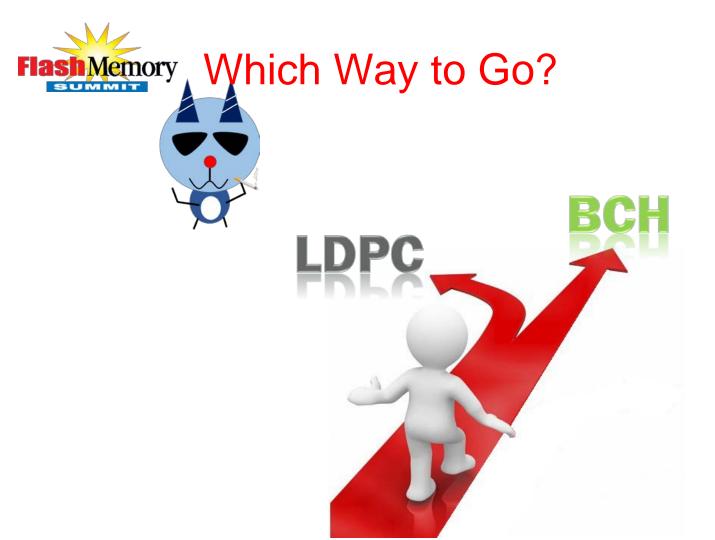




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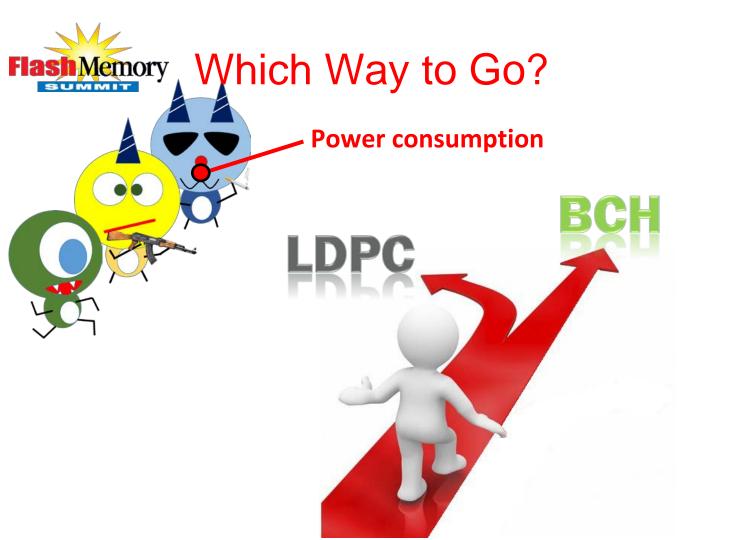


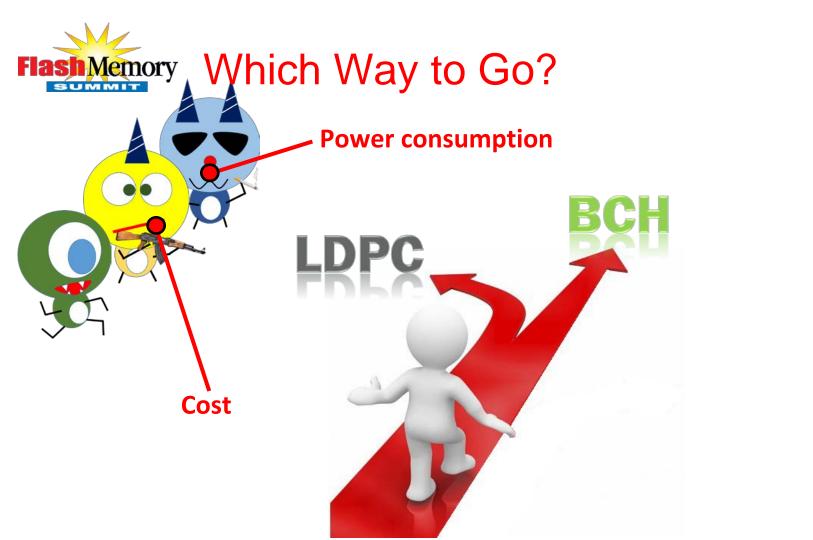


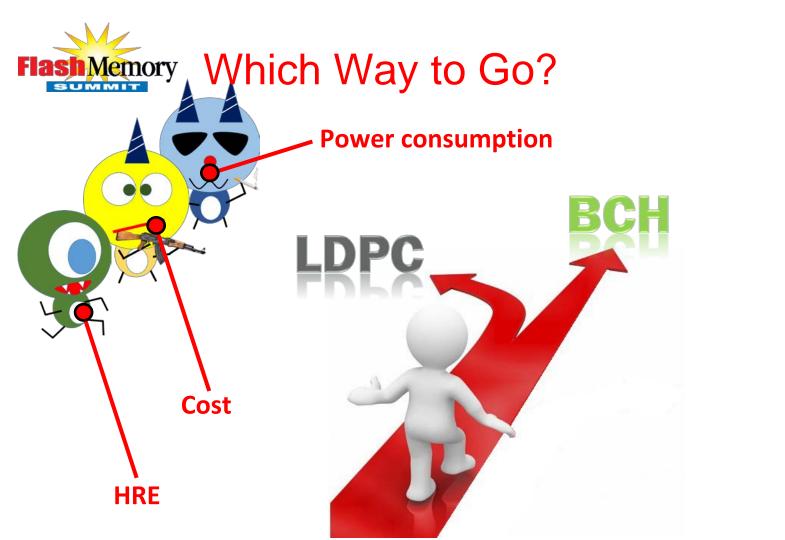


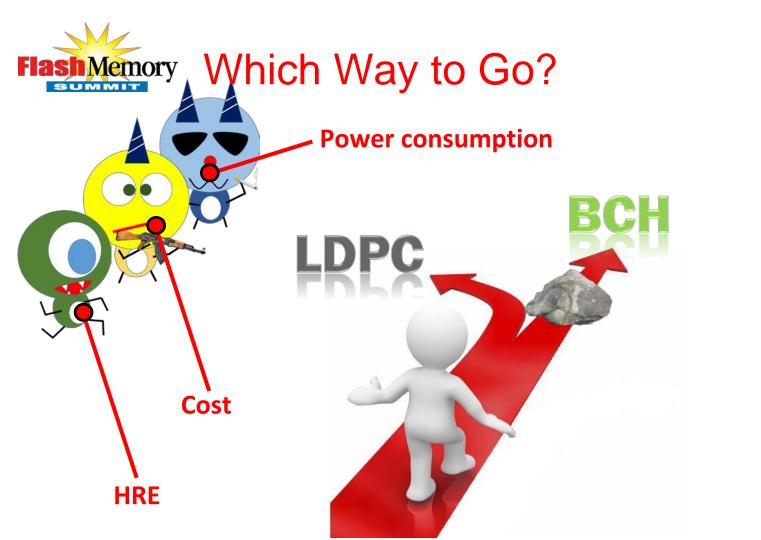


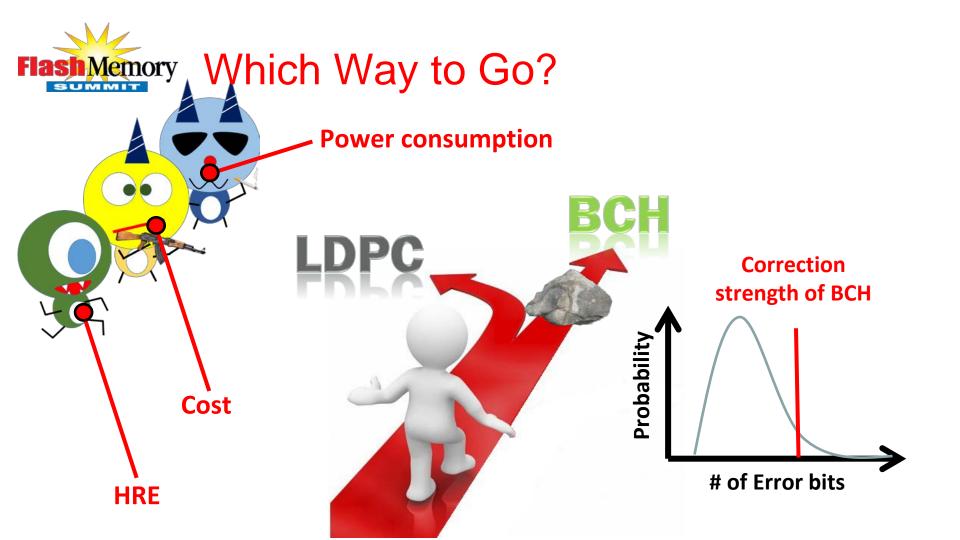




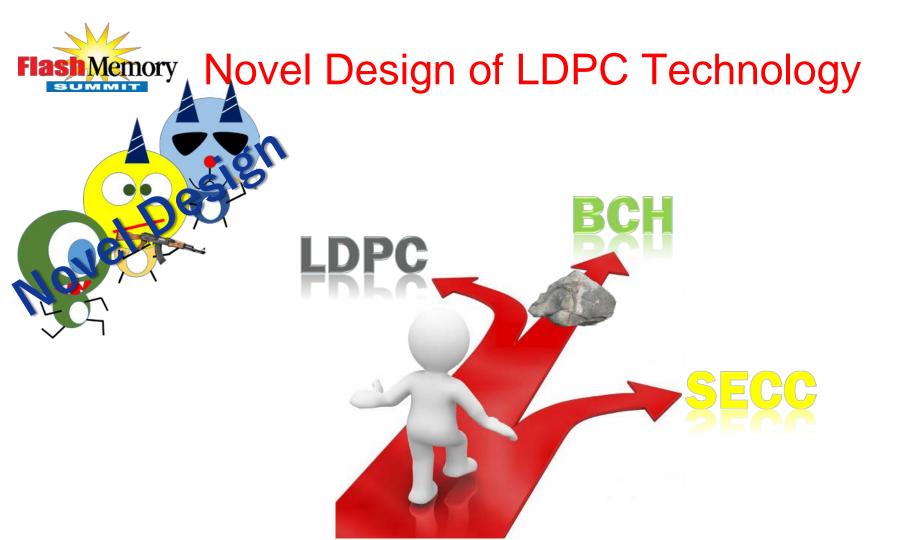


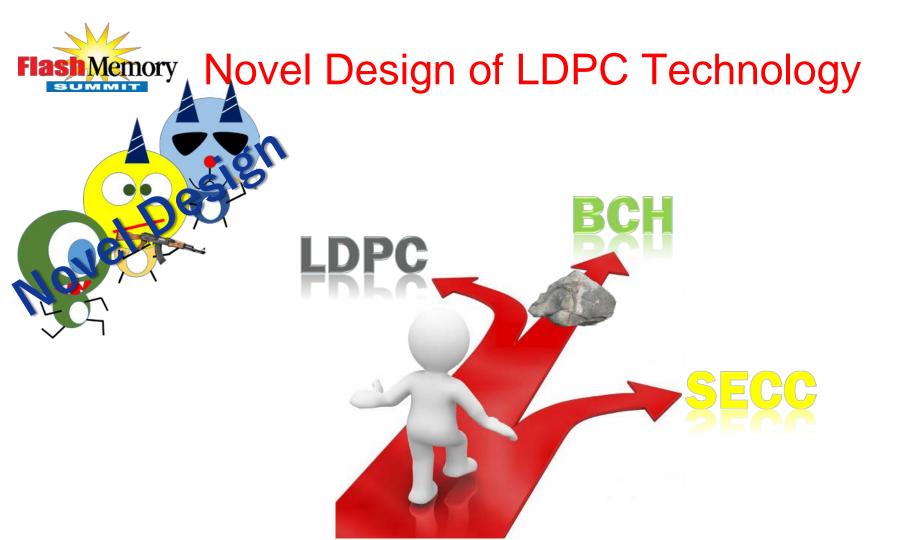














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#### Flash Memory Comparison between ECC tech

	Conventional LDPC	ВСН
Decoding Algorithm	Probability Based	Algebraic Based
Guaranteed Correction Strength	No	Yes
Soft Bit Decoding	Easy	Hard
Performance of Hard Decoding	Similar to BCH	Code Length * (1-code rate) Degree of polynomial
Performance of Soft Decoding	2X than BCH	-
Decoding Complexity	High	Low
Power consumption	High	Mid
Cost	High	Low

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### Flash Memory Comparison between ECC of Phison

	4K LDPC	4K LDPC Lite	SECC	ВСН
Decoding Algorithm	Probability Based	Probability Based	Probability Based	Algebraic Based
Guaranteed Correction Strength	No	No	No	Yes
Soft Bit Decoding	Easy	Easy	Easy	Hard
Performance of Hard Decoding	1.3X BCH	Similar to BCH	1.3X than BCH	Code Length * (1-code rate) Degree of polynomial
Performance of Soft Decoding	2X-3X than HB	2X than BCH	1.7X than BCH	-
Decoding Complexity	Mid	Mid	Low	Low
Power consumption	Low	Low	Low	Mid
Cost	High	Mid	Low	Low



## Flash Memory ECC Technology of Phison

	Correction Strength	Gate Count	Technology node (nm)	Support NAND	Q3' 2016	Q4' 2016	2017
1K BCH	72/1K	260K	55/40/28	2D/3D MLC/TLC	Applied	d for USB/SD/eMM	IC/SSD
2К ВСН	120/2К	540K	55	2D/3D MLC/TLC	Applied for SSD		
SECC	95&135/1K	300K	40	2D/3D MLC/TLC/QLC	Applied for SD/eMMC/UFS/SSD		FS/SSD
4K LDPC Lite	72&150/1K	0.7M	40	2D/3D MLC/TLC/QLC	Applied for SSD		
4K LDPC	85&200/1K	1M	28	2D/3D MLC/TLC/QLC		Applied	for SSD
Matrix ECC	-	300K	55/40/28	2D/3D MLC/TLC/QLC	Applied for SSD/UFS		



#### Flash Memory Comparison between ECC of Phison

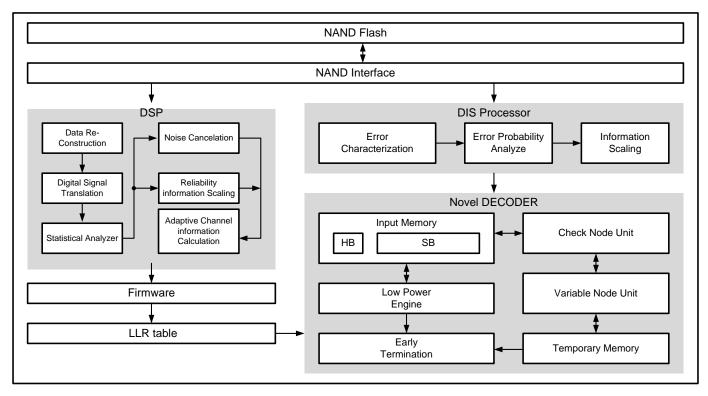
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#### Comparison between ECC of Phison **Flash** Memory

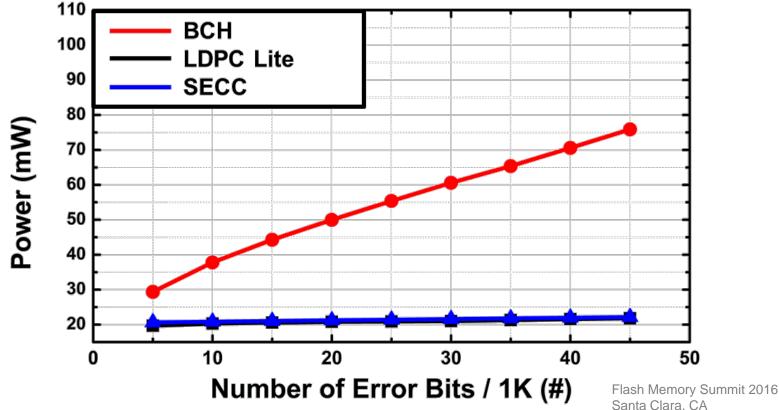


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#### Flash Memory Comparison between ECC of Phison

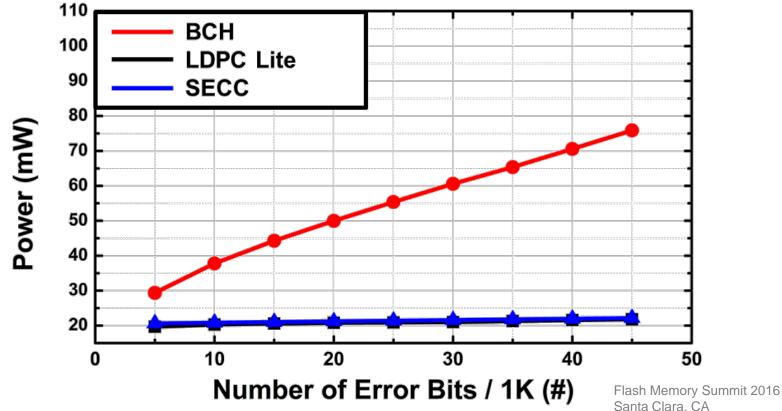
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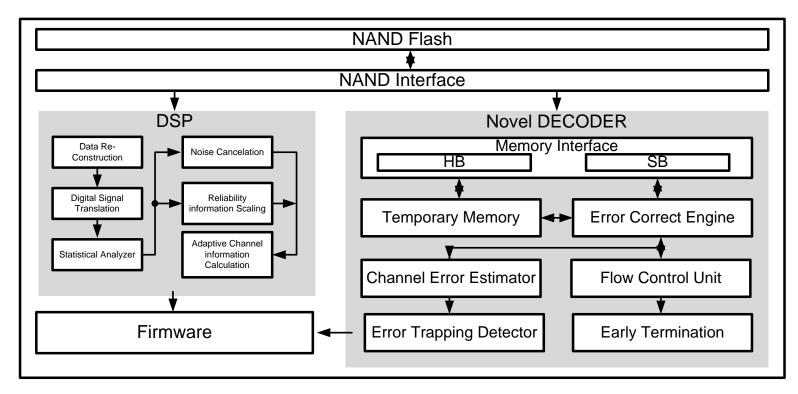
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Decoding Complexity				Low
Power consumption				Mid
Cost				Low



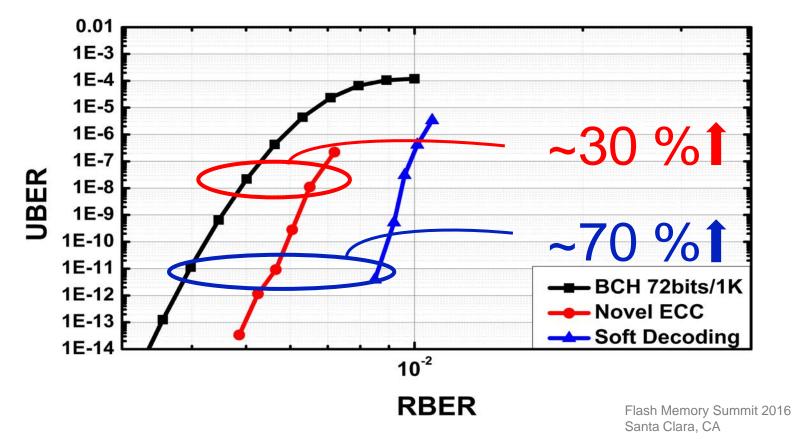




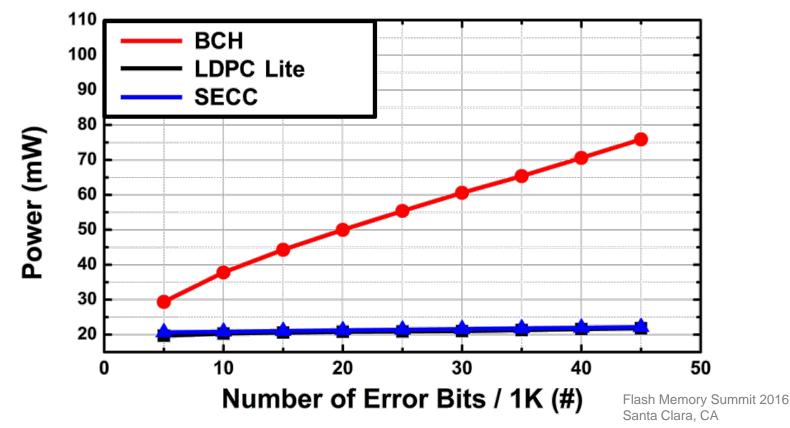




#### Flash Memory Correction Capability of SECC



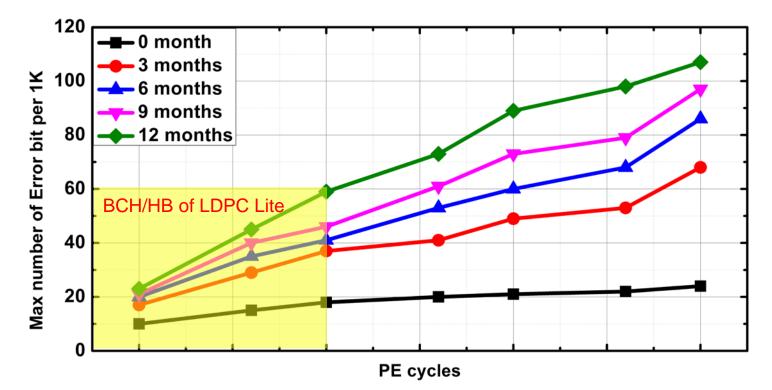




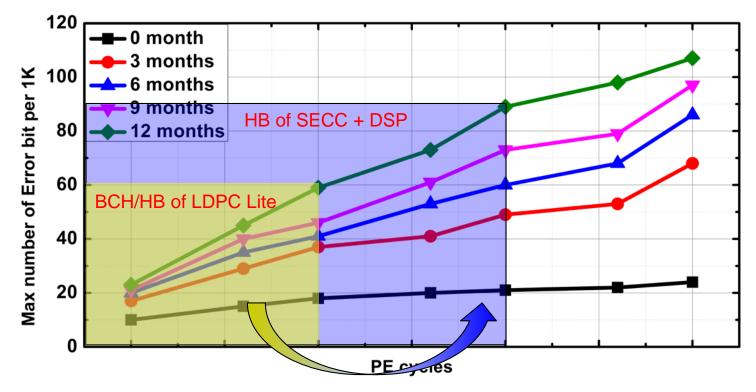


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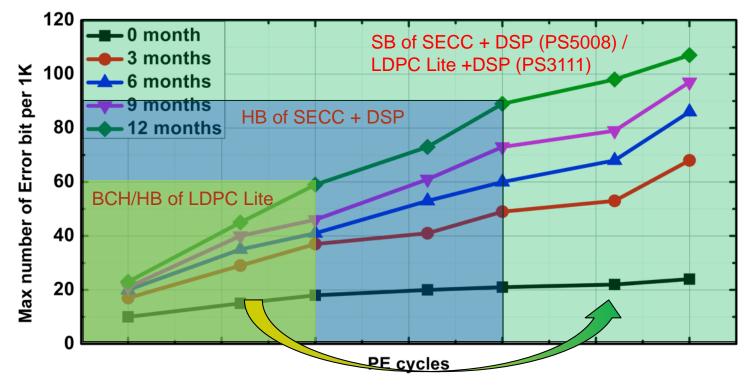




2X Extended



#### **Reliability Improvement of 3D NAND**



>3X Extended



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- The power consumption of the LDPC lite and SECC engine are only 1/3 than the convention BCH.
- With the novel design of decoding algorithm, the cost of LDPC can be reduced effectively.
- The endurance of 3D NAND Flash can be 3X more extended by SECC and LDPC lite with DSP engine.

# Flash Memory Meet us at booth 714 & 716



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